

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

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WARREN M. FARNWORTH
SALMAN AKRAM
ALAN G. WOOD
C. PATRICK DOHERTY
ANDREW J. KRIVY

ART UNIT:

EXAMINER:

Division of Serial No. 09/929,388
filed August 14, 2001

Filing Date: February 5, 2002

Title: METHOD FOR TESTING
SEMICONDUCTOR WAFERS (as amended)

Docket No. 96-750.3

TRANSMITTAL LETTER TO THE OFFICIAL DRAFTSPERSON
February 5, 2002

BOX PATENT APPLICATION
Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Please substitute the attached new formal drawings (six sheets) for the drawings originally filed in parent application serial no. 08/797,719. The new formal drawings have improved line and character quality.

Respectfully submitted:


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Attorney of Record
Registration No. 28,418

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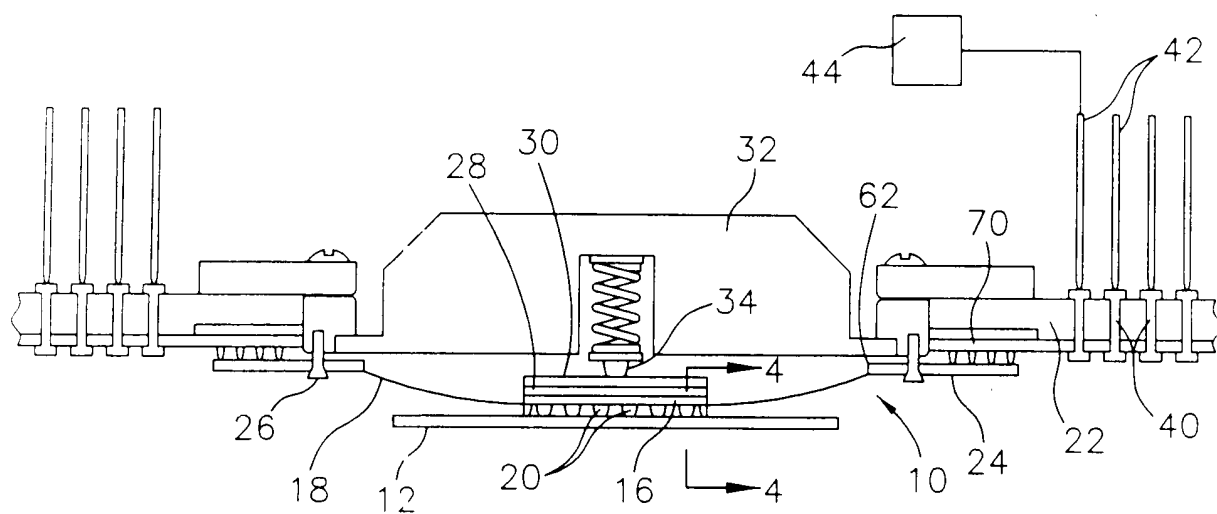


FIGURE 1

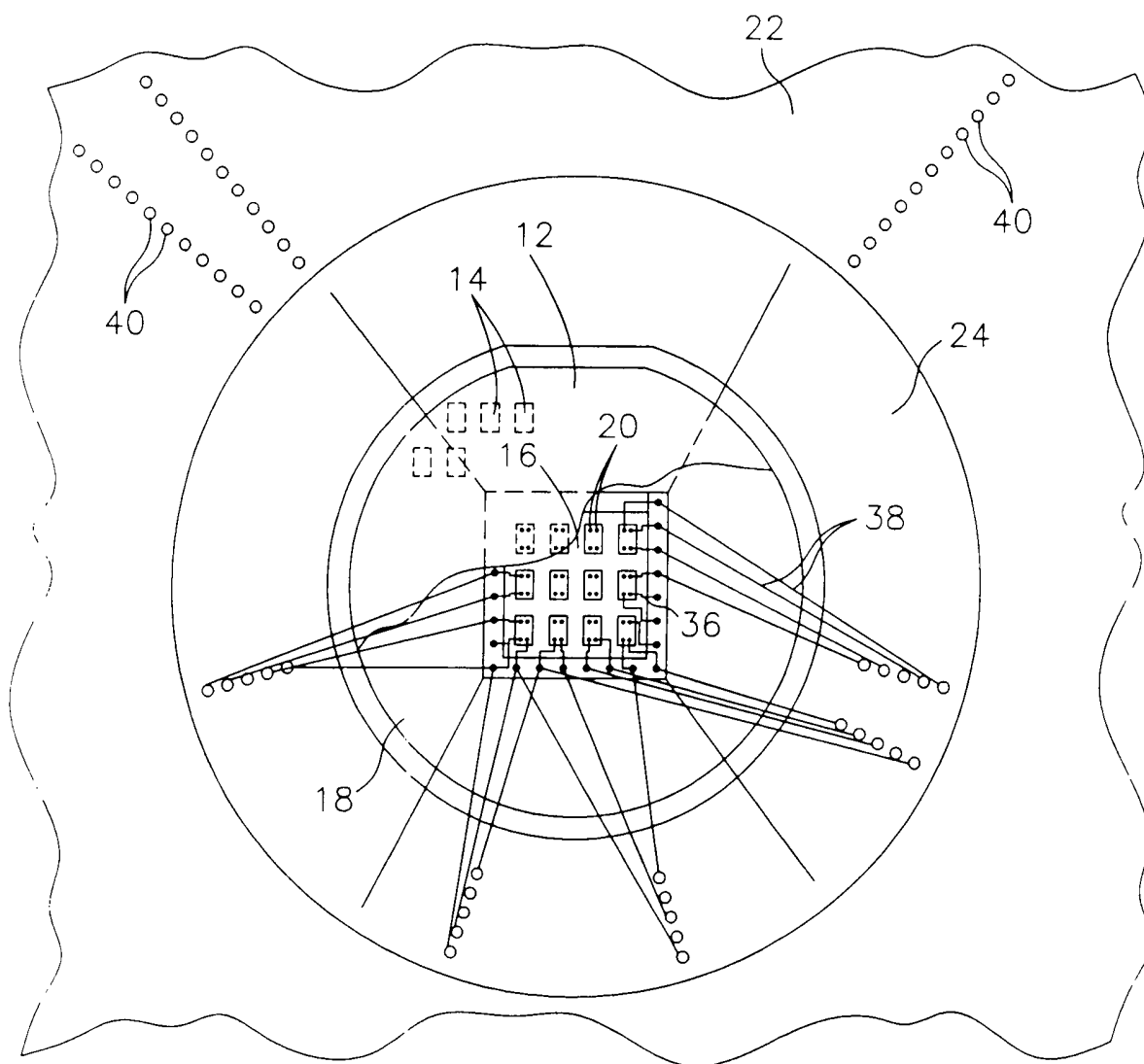


FIGURE 2

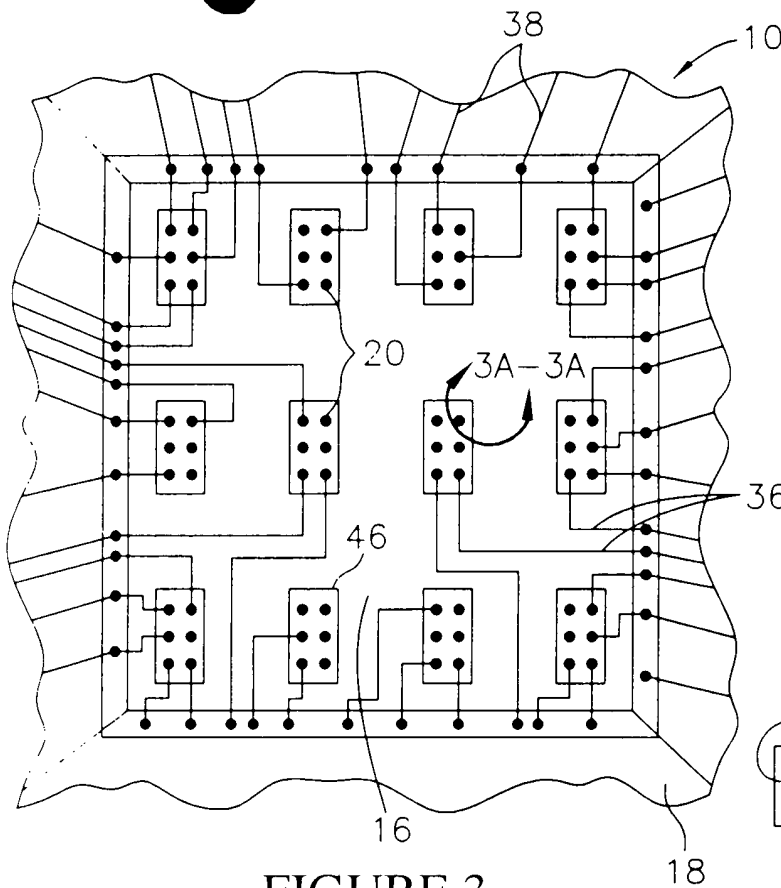


FIGURE 3

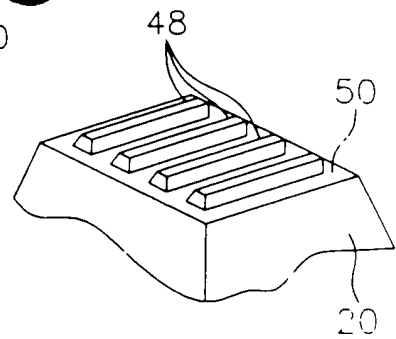


FIGURE 3A

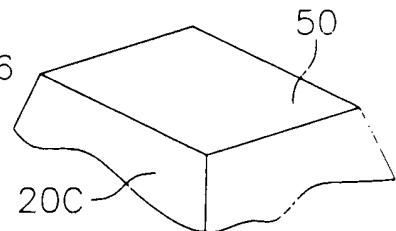


FIGURE 3B

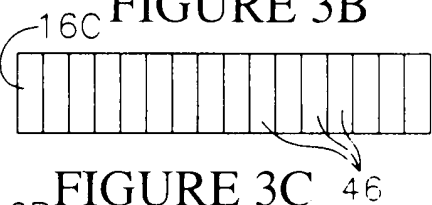


FIGURE 3C

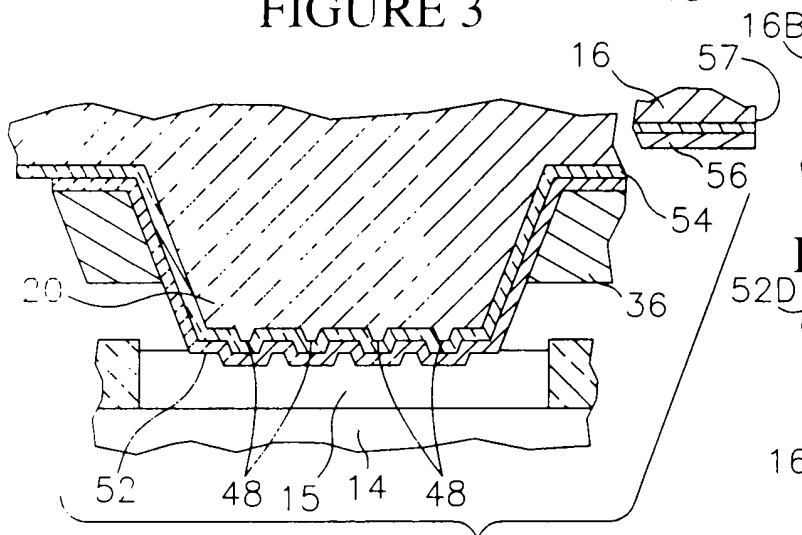


FIGURE 4

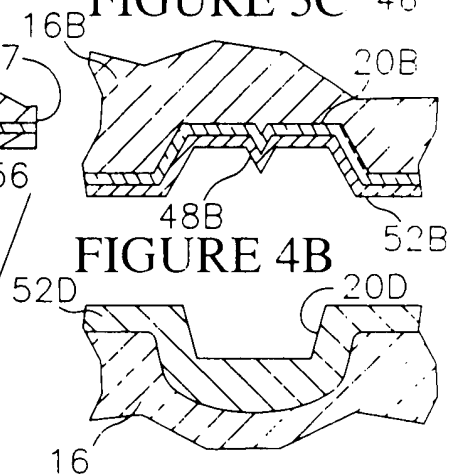


FIGURE 4B

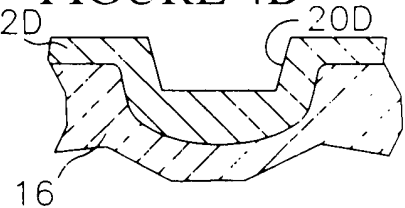


FIGURE 4D

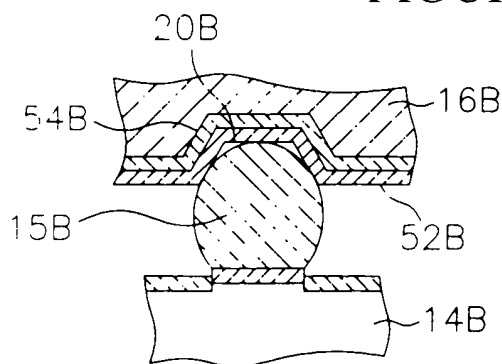


FIGURE 4A

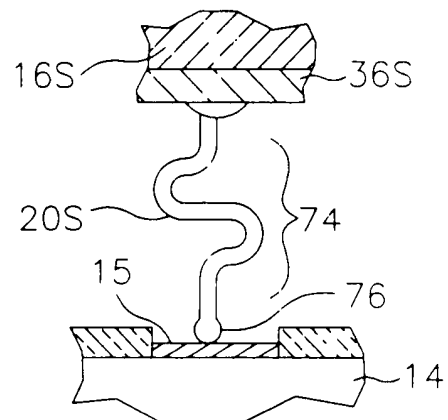


FIGURE 4C

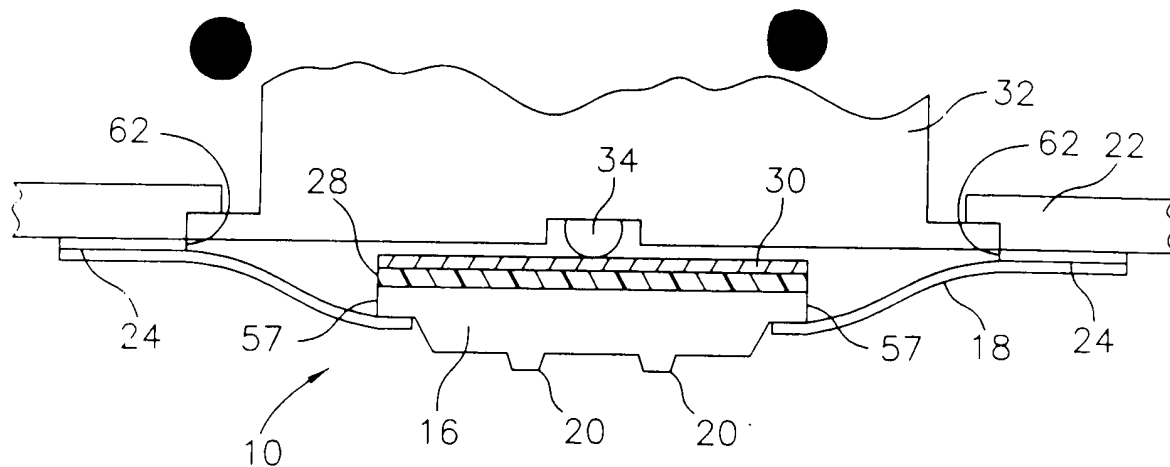


FIGURE 5

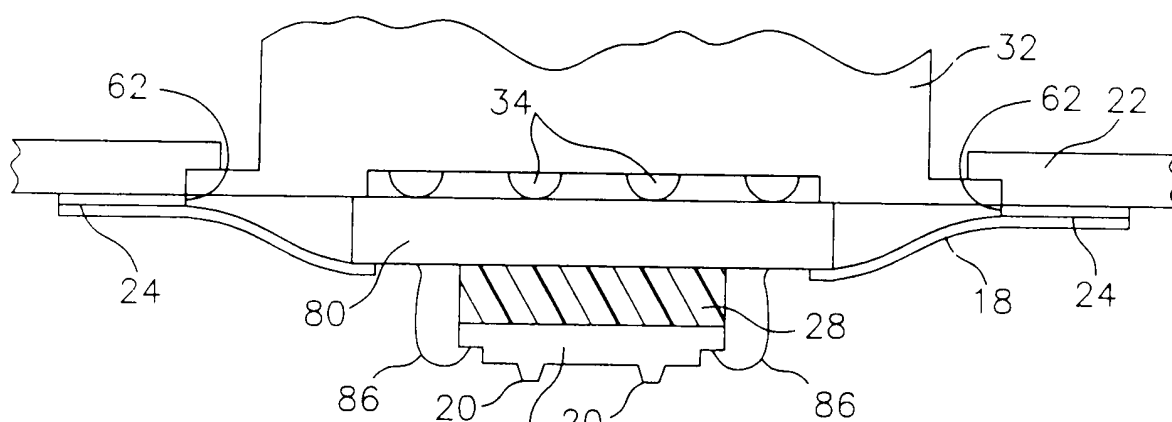


FIGURE 5A

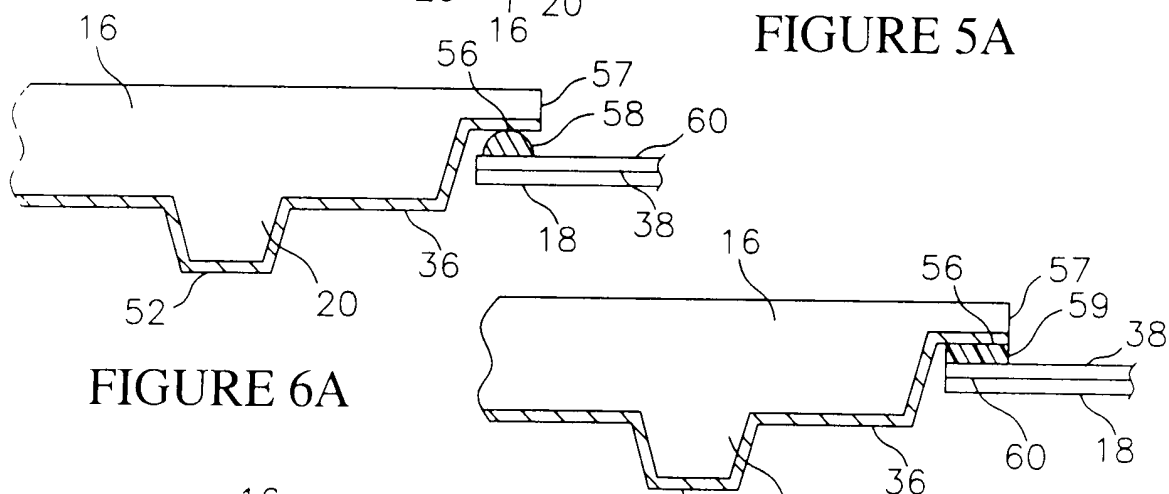


FIGURE 6A

FIGURE 6B

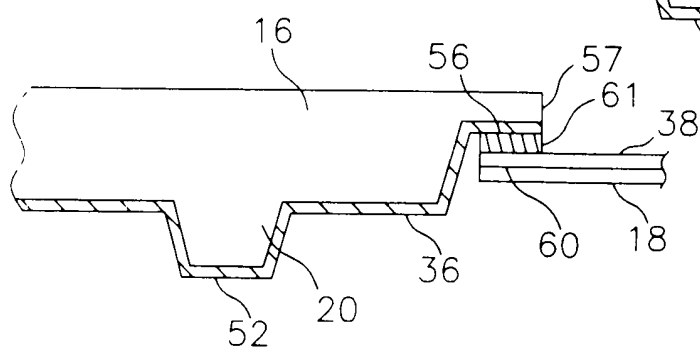


FIGURE 6C

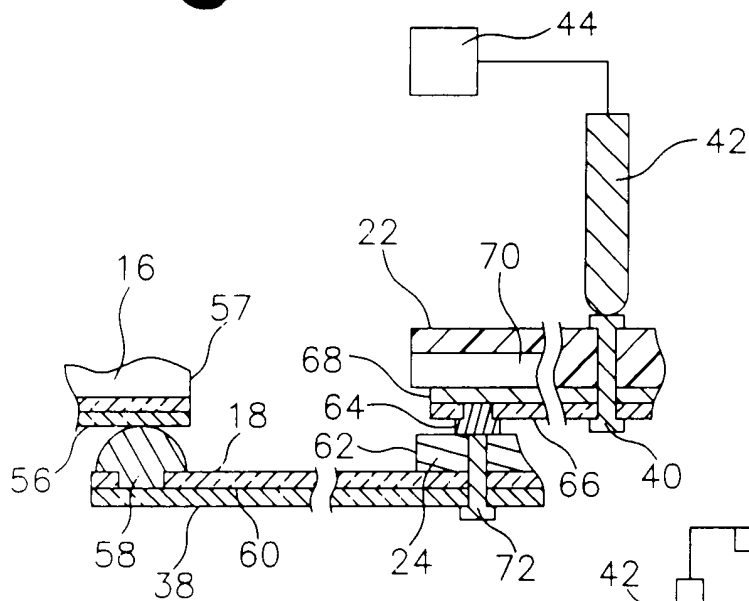


FIGURE 7A

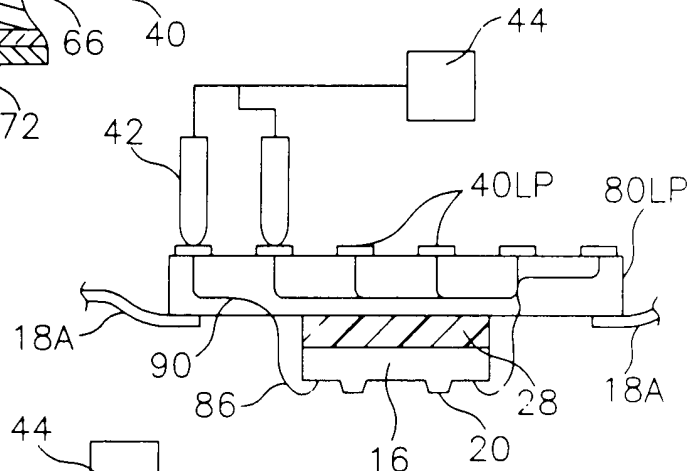


FIGURE 7B

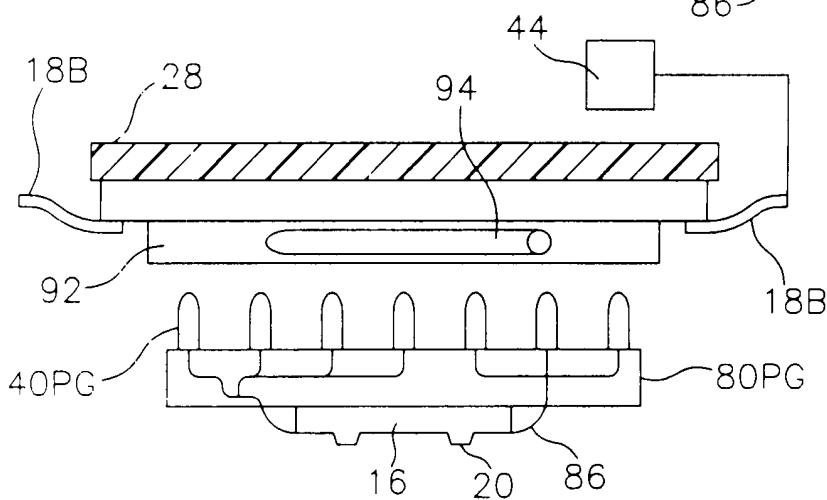


FIGURE 7C

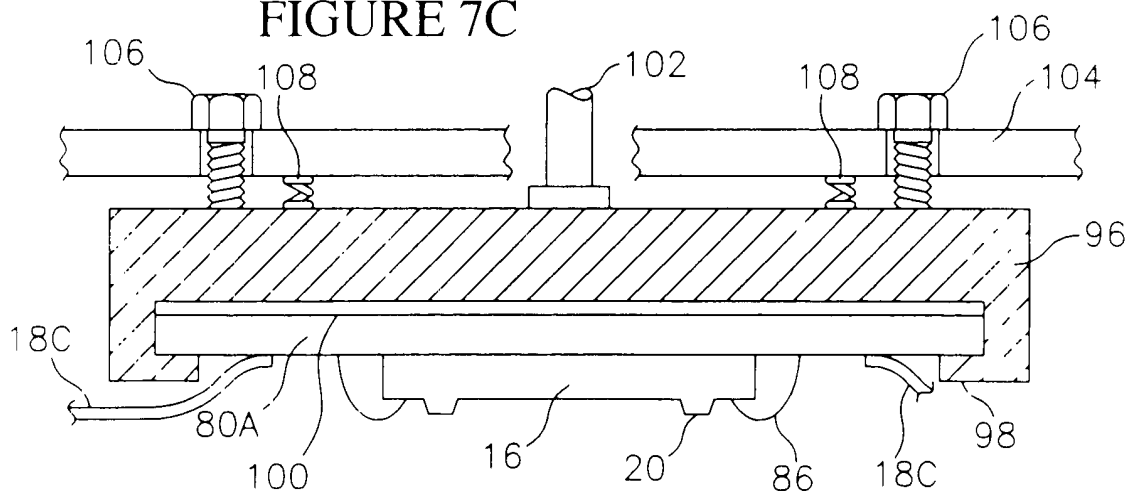


FIGURE 7D

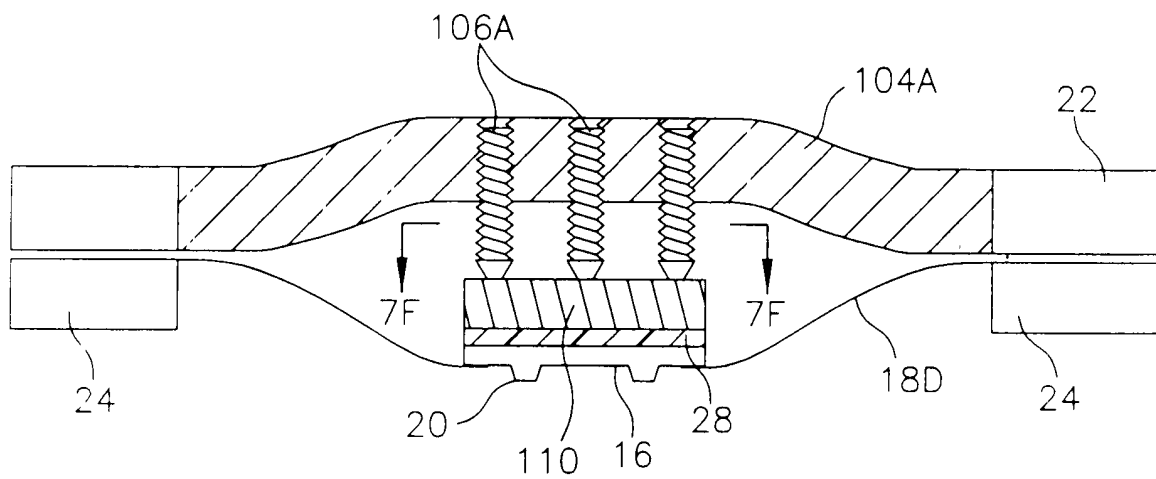


FIGURE 7E

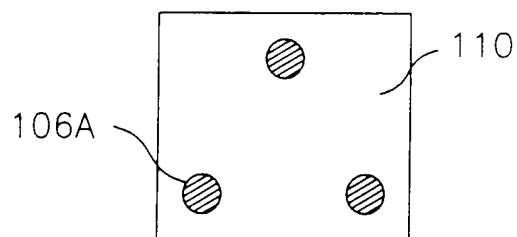


FIGURE 7F

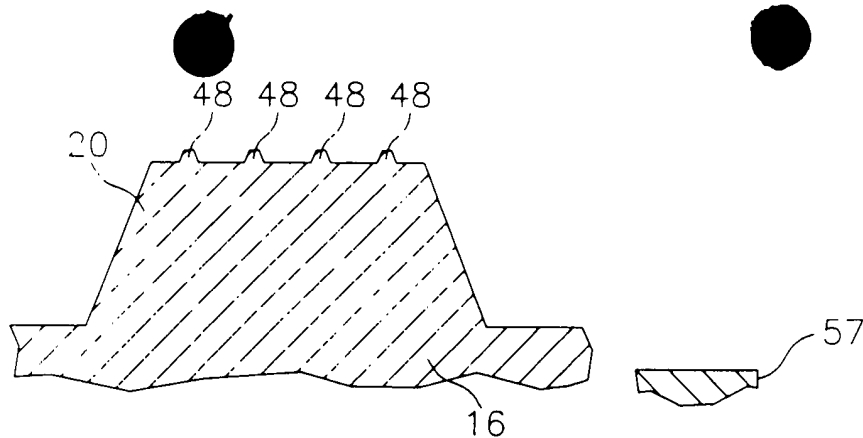


FIGURE 9A

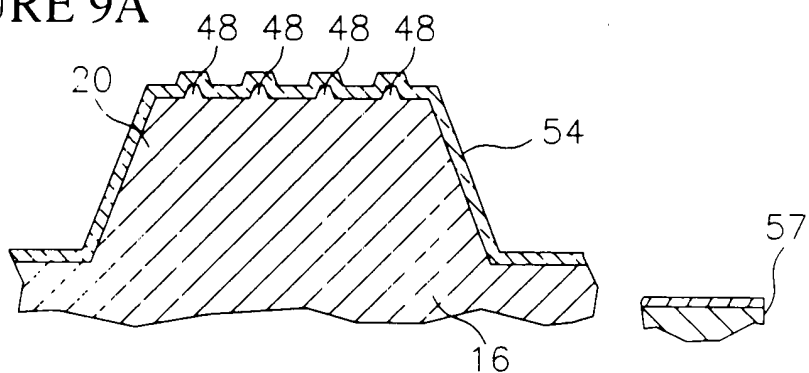


FIGURE 9B

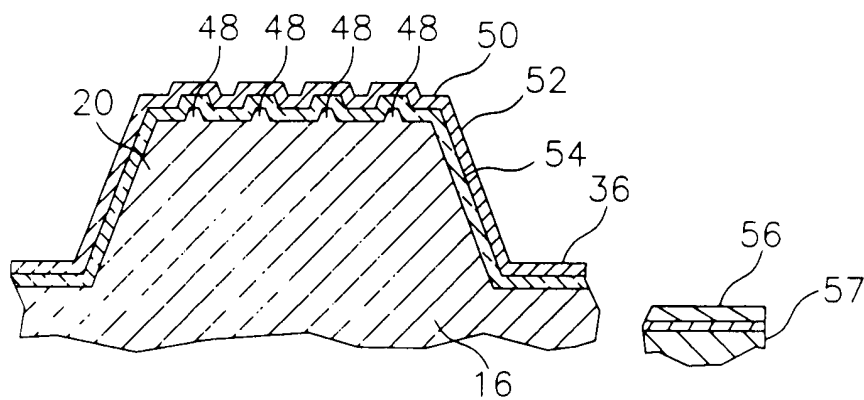


FIGURE 9C

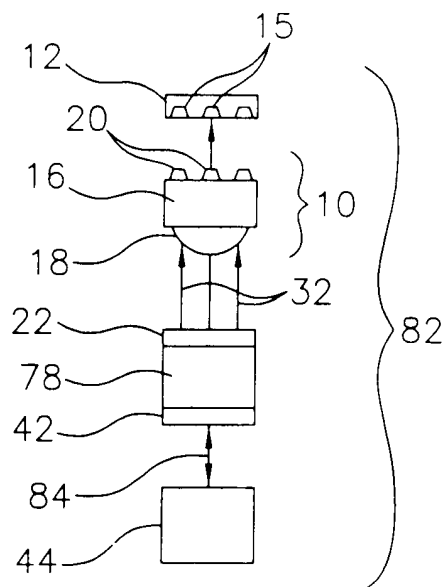


FIGURE 8